26/08/04
20040048112

(12) INTERNATIONAL APPLICATION PUBLISHED UNDER THE PATENT COOPERATION TREATY (PCT)

(19) World Intellectual Property Organization
International Bureau

(43) International Publication Date
12 September 2003 (12.09.2003)

PCT

(10) International Publication Number
WO 03/075190 A1

(51) International Patent Classification[7]: G06F 17/50

(21) International Application Number: PCT/US03/05959

(22) International Filing Date: 27 February 2003 (27.02.2003)

(25) Filing Language: English

(26) Publication Language: English

(30) Priority Data:
60/360,304 28 February 2002 (28.02.2002) US

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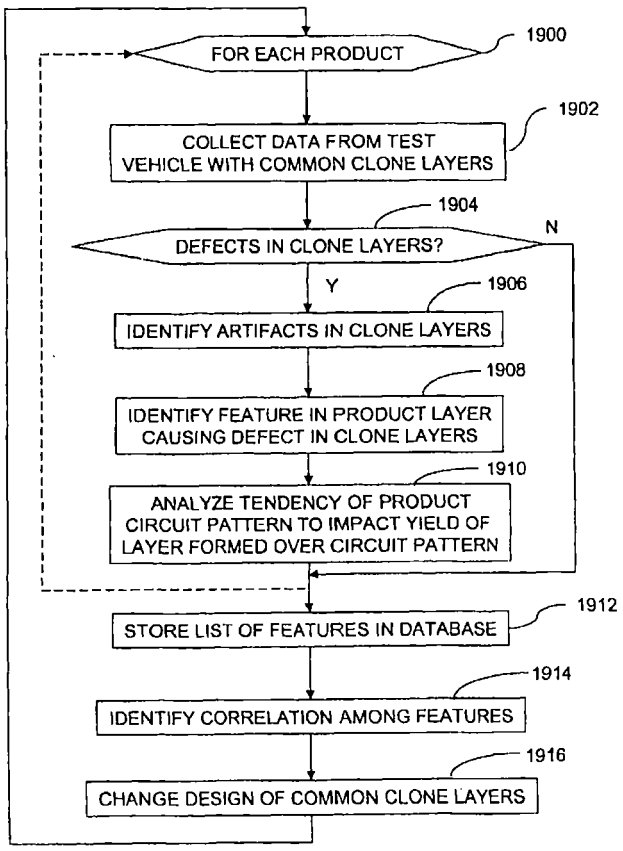
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(81) Designated States *(national)*: AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BY, BZ, CA, CH, CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, ES, FI, GB, GD, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW, MX, MZ, NO, NZ, OM, PH, PL, PT, RO, RU, SD, SE, SG, SK, SL, TJ, TM, TN, TR, TT, TZ, UA, UG, US, UZ, VN, YU, ZA, ZM, ZW.

(84) Designated States *(regional)*: ARIPO patent (GH, GM, KE, LS, MW, MZ, SD, SL, SZ, TZ, UG, ZM, ZW), Eurasian patent (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM),

[Continued on next page]

(54) Title: BACK END OF LINE CLONE TEST VEHICLE



(57) Abstract: A test vehicle comprises at least one product layer having at least one product circuit pattern on the product layer, and one or more clone layers formed over the product layer (1902). The one or more clone layers include a plurality of structures, which may include clone test vehicle circuit patterns and/or clone test vehicle vias (1902). The presence of one or more defects (1904) in the one or more clone layers (1908) is an indicator of a tendency of the product circuit pattern to impact yield of a succeeding layer to be formed over the product circuit pattern in a product (1910).

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European patent (AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES, FI, FR, GB, GR, HU, IE, IT, LU, MC, NL, PT, SE, SI, SK, TR), OAPI patent (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG).

Published:

— *with international search report*

— *before the expiration of the time limit for amending the claims and to be republished in the event of receipt of amendments*

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